IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Prior Application:

N. KATOH et al

Serial No. 10/084,435 Filed: February 28, 2002

Group Art Unit:

2825

Examiner:

P. Kik

For:

SEMICONDUCTOR INTEGRATED CIRCUIT DEVICE, STORAGE MEDIUM ON WHICH CELL LIBRARY IS STORED AND DESIGNING METHOD FOR SEMICONDUCTOR INTEGRATED CIRCUIT

INFORMATION DISCLOSURE STATEMENT

Commissioner for Patents Mail Stop Patent Application P.O. Box 1450 Alexandria, VA 22313-1450

Sir:

In accordance with the duty of disclosure, the Applicants inform the Examiner of the documents cited during prosecution of the parent application, U.S. Serial No. 10/084,435.

The Applicants request the Examiner to initial and return a copy of the attached PTO-1449 form as an indication that the references have been considered.

Respectfully submitted,

Shrinath Malur

Registration No. 34,663

Leus W Stockman RN21,021

Attorney of Record

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Date: April 20, 2004

FORM PTO-1449 (REV. 7-80)		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		NIT-201-03		SERIAL NO.					
LIST OF DOCUMENTS CITED BY A					APPLICANT N. KATOH et al FILING DATE	GR	GROUP				
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